

# PSMN3R5-30YL

# N-channel 30 V 3.5 m $\Omega$ logic level MOSFET in LFPAK Rev. 4 — 9 March 2011 Product

**Product data sheet** 

#### **Product profile** 1.

## 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in industrial and communications applications.

## 1.2 Features and benefits

- High efficiency due to low switching and conduction losses
- Suitable for logic level gate drive sources

## 1.3 Applications

- Class-D amplifiers
- DC-to-DC converters

- Motor control
- Server power supplies

## 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	30	V
I <sub>D</sub>	drain current	$T_{mb} = 25 ^{\circ}\text{C};  V_{GS} = 10 \text{V};$ see Figure 1	[1]	-	-	100	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	-	74	W
Tj	junction temperature			-55	-	175	°C
Static chara	acteristics						
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}$		-	2.43	3.5	mΩ
Dynamic ch	naracteristics						
$Q_{GD}$	gate-drain charge	$V_{GS} = 4.5 \text{ V}; I_D = 10 \text{ A};$		-	5	-	nC
$Q_{G(tot)}$	total gate charge	V <sub>DS</sub> = 12 V; see <u>Figure 14;</u> see <u>Figure 15</u>		-	19	-	nC
Avalanche	ruggedness						
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$V_{GS}$ = 10 V; $T_{j(init)}$ = 25 °C; $I_D$ = 100 A; $V_{sup} \le$ 30 V; $R_{GS}$ = 50 Ω; unclamped		-	-	54	mJ

<sup>[1]</sup> Continuous current is limited by package.



# 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source		
2	S	source	mb	B
3	S	source		
4	G	gate	9	
mb	D	mounting base; connected to drain	1 2 3 4	mbb076 Ś
			SOT669 (LFPAK)	

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PSMN3R5-30YL	LFPAK	plastic single-ended surface-mounted package (LFPAK); 4 leads	SOT669

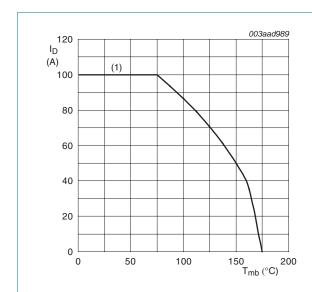
## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

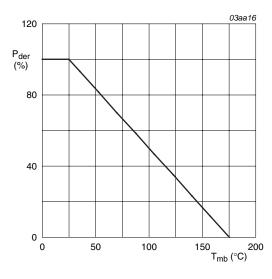
Parameter	Conditions	Min	Max	Unit
drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	30	V
peak drain-source voltage	$t_p \le 25$ ns; $f \le 500$ kHz; $E_{DS(AL)} \le 180$ nJ; pulsed	-	35	V
drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	30	V
gate-source voltage		-20	20	V
drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	<u>[1]</u> -	86	Α
	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u>	<u>[1]</u> -	100	Α
peak drain current	pulsed; $t_p \le 10 \mu s$ ; $T_{mb} = 25 \text{ °C}$ ; see Figure 3	-	447	Α
total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	74	W
storage temperature		-55	175	°C
junction temperature		-55	175	°C
diode				
source current	T <sub>mb</sub> = 25 °C	<u>[1]</u> _	100	Α
peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$	-	447	Α
ggedness				
non-repetitive drain-source avalanche energy	$V_{GS} = 10 \text{ V; } T_{j(init)} = 25 \text{ °C; } I_D = 100 \text{ A;}$ $V_{sup} \le 30 \text{ V; } R_{GS} = 50 \text{ Ω; unclamped}$	-	54	mJ
	drain-source voltage  peak drain-source voltage  drain-gate voltage  gate-source voltage  drain current  peak drain current  total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source	$\begin{array}{ll} \text{drain-source voltage} & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} \\ \\ \text{peak drain-source voltage} & t_{p} \leq 25 \ \text{ns}; \ f \leq 500 \ \text{kHz}; \\ E_{DS(AL)} \leq 180 \ \text{nJ}; \ \text{pulsed} \\ \\ \text{drain-gate voltage} & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C}; \ R_{GS} = 20 \ \text{k}\Omega \\ \\ \text{gate-source voltage} \\ \\ \text{drain current} & V_{GS} = 10 \ \text{V}; \ T_{mb} = 100 \ ^{\circ}\text{C}; \ \text{see } \underline{\text{Figure 1}} \\ \\ V_{GS} = 10 \ \text{V}; \ T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see } \underline{\text{Figure 1}} \\ \\ \text{peak drain current} & \text{pulsed; } t_{p} \leq 10 \ \text{\mus}; \ T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see} \\ \\ \underline{\text{Figure 3}} \\ \\ \text{total power dissipation} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see} \ \underline{\text{Figure 2}} \\ \\ \text{storage temperature} \\ \\ \underline{\text{junction temperature}} \\ \\ \underline{\text{diode}} \\ \\ \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ \text{peak source current} & \text{pulsed; } t_{p} \leq 10 \ \text{\mus}; \ T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ \underline{\text{ggedness}} \\ \\ \text{non-repetitive drain-source} & V_{GS} = 10 \ \text{V}; \ T_{j(\text{init})} = 25 \ ^{\circ}\text{C}; \ I_{D} = 100 \ \text{A}; \\ \\ \end{array}$	$\begin{array}{llllllllllllllllllllllllllllllllllll$	$\begin{array}{llllllllllllllllllllllllllllllllllll$

## [1] Continuous current is limited by package.



 $V_{\rm GS} \geq$  10 V; (1) Capped at 100 A due to package

Fig 1. Continuous drain current as a function of mounting base temperature



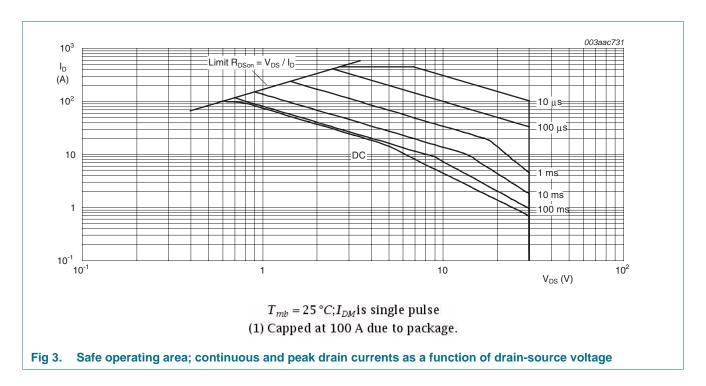
 $P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$ 

Fig 2. Normalized total power dissipation as a function of mounting base temperature

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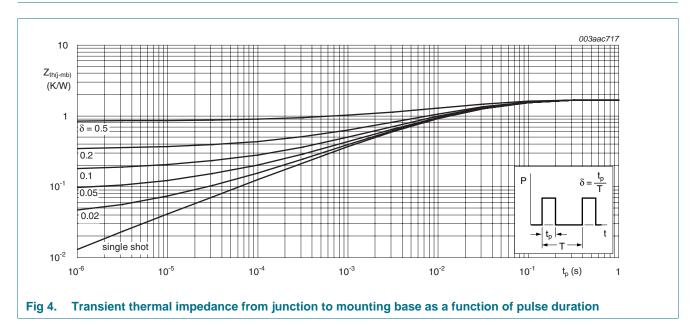
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## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	0.6	1.68	K/W



## 6. Characteristics

Table 6. Characteristics

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	cteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	27	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	1.3	1.7	2.15	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 150$ °C; see Figure 12	0.65	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see Figure 12	-	-	2.45	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μA
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 ^{\circ}\text{C}$	-	-	100	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
		$V_{GS} = -16 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	100	nΑ
R <sub>DSon</sub>	drain-source on-state	$V_{GS} = 4.5 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	3.37	4.61	mΩ
resistance	resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 150 \text{ °C};$ see Figure 13	-	-	6	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A}; T_j = 25 \text{ °C}$	-	2.43	3.5	mΩ
R <sub>G</sub>	gate resistance	f = 1 MHz	-	0.53	1.5	Ω
Dynamic ch	aracteristics					
Q <sub>G(tot)</sub> to	total gate charge	$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ; see Figure 14; see Figure 15	-	19	-	nC
		$I_D = 0 \text{ A}; V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}$	-	37	-	nC
		$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 10 \text{ V}$ ; see Figure 14; see Figure 15	-	41	-	nC
Q <sub>GS</sub>	gate-source charge	$I_D = 10 \text{ A}$ ; $V_{DS} = 12 \text{ V}$ ; $V_{GS} = 4.5 \text{ V}$ ;	-	6	-	nC
Q <sub>GS(th)</sub>	pre-threshold gate-source charge	see <u>Figure 14</u> ; see <u>Figure 15</u>	-	4	-	nC
Q <sub>GS(th-pl)</sub>	post-threshold gate-source charge		-	2	-	nC
$Q_{GD}$	gate-drain charge		-	5	-	nC
V <sub>GS(pI)</sub>	gate-source plateau voltage	V <sub>DS</sub> = 12 V; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	2.4	-	V
C <sub>iss</sub>	input capacitance	V <sub>DS</sub> = 12 V; V <sub>GS</sub> = 0 V; f = 1 MHz;	-	2458	-	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	532	-	pF
C <sub>rss</sub>	reverse transfer capacitance		-	252	-	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 12 \text{ V}; R_L = 0.5 \Omega; V_{GS} = 4.5 \text{ V};$	-	33	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 4.7 \Omega$	-	50	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	45	-	ns
t <sub>f</sub>	fall time		-	18	-	ns

 Table 6.
 Characteristics ...continued

Tested to JEDEC standards where applicable.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-drain	diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}$ ; $V_{GS} = 0 \text{ V}$ ; $T_j = 25 \text{ °C}$ ; see <u>Figure 17</u>	-	0.82	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	37	-	ns
Q <sub>r</sub>	recovered charge	$V_{DS} = 20 \text{ V}$	-	31	-	nC

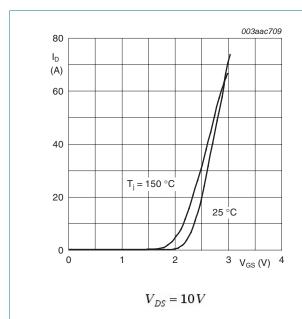
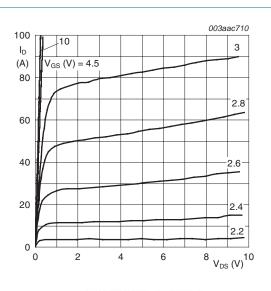


Fig 5. Transfer characteristics: drain current as a function of gate-source voltage; typical values



$$T_j = 25 \,^{\circ}C; t_p = 300 \,\mu s$$

Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

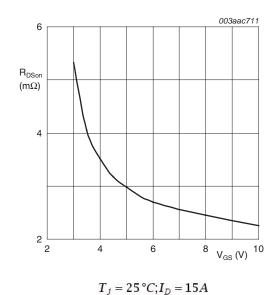
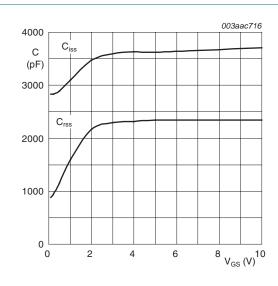


Fig 7. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $V_{DS} = 0V; f = 1MHz$ 

Fig 8. Input and reverse transfer capacitances as a function of gate-source voltage; typical values

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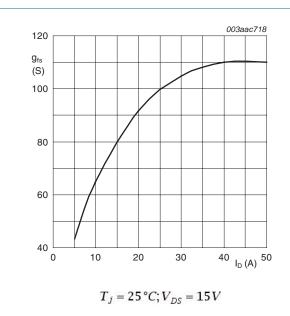


Fig 9. Forward transconductance as a function of drain current; typical values

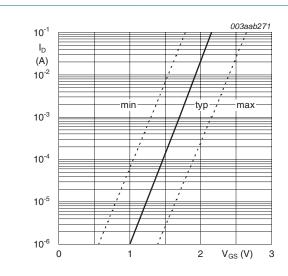
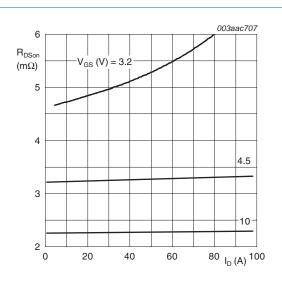


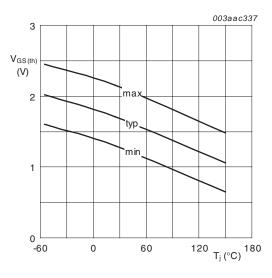
Fig 11. Sub-threshold drain current as a function of gate-source voltage

 $T_j = 25 \,^{\circ}C; V_{DS} = 5V$ 



 $T_j = 25 \,^{\circ}C; t_p = 300 \mu s$ 

Fig 10. Drain-source on-state resistance as a function of drain current; typical values



 $I_D = 1mA; V_{DS} = V_{GS}$ 

Fig 12. Gate-source threshold voltage as a function of junction temperature

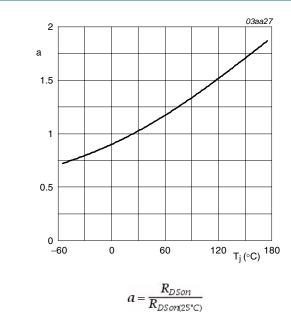


Fig 13. Normalized drain-source on-state resistance factor as a function of junction temperature

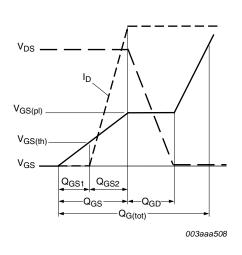


Fig 14. Gate charge waveform definitions

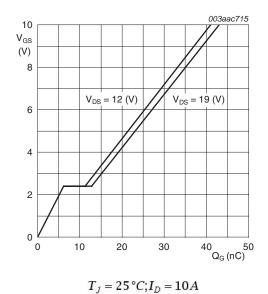
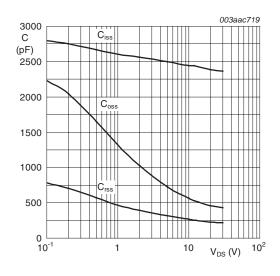


Fig 15. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$ 

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

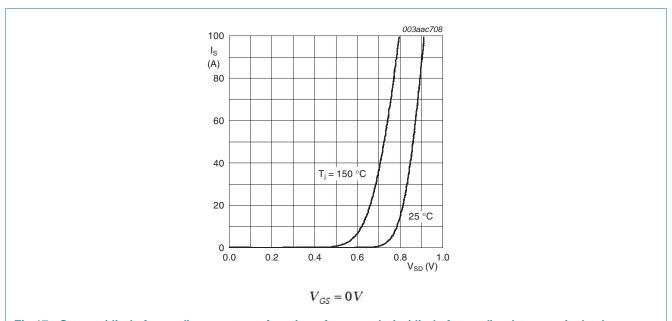


Fig 17. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values

## 7. Package outline

## Plastic single-ended surface-mounted package (LFPAK); 4 leads

**SOT669** 

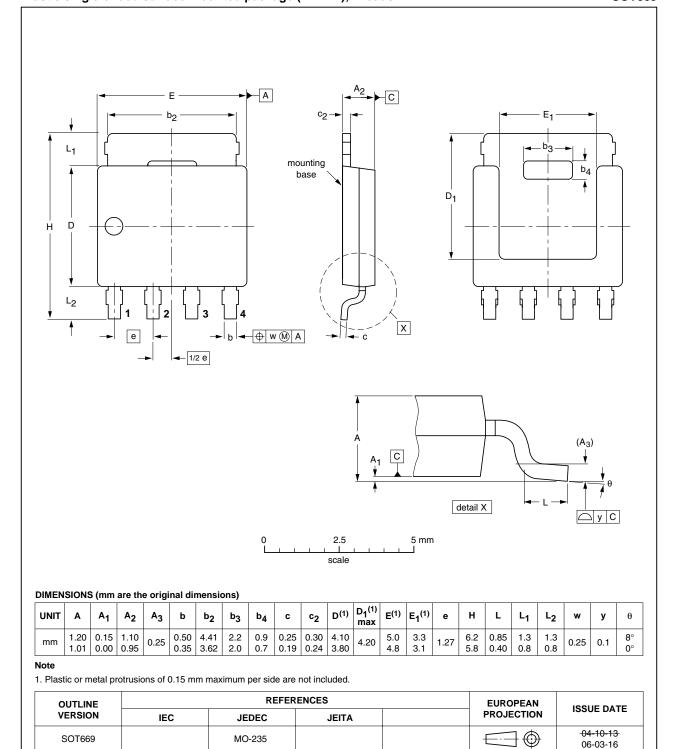


Fig 18. Package outline SOT669 (LFPAK)

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# 8. Revision history

## Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PSMN3R5-30YL v.4	20110309	Product data sheet	-	PSMN3R5-30YL_3
Modifications:	<ul> <li>Various changes</li> </ul>	s to content.		
PSMN3R5-30YL_3	20091231	Product data sheet	-	PSMN3R5-30YL_2

## 9. Legal information

#### 9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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## N-channel 30 V 3.5 mΩ logic level MOSFET in LFPAK

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# PSMN3R5-30YL

## **NXP Semiconductors**

## N-channel 30 V 3.5 m $\Omega$ logic level MOSFET in LFPAK

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